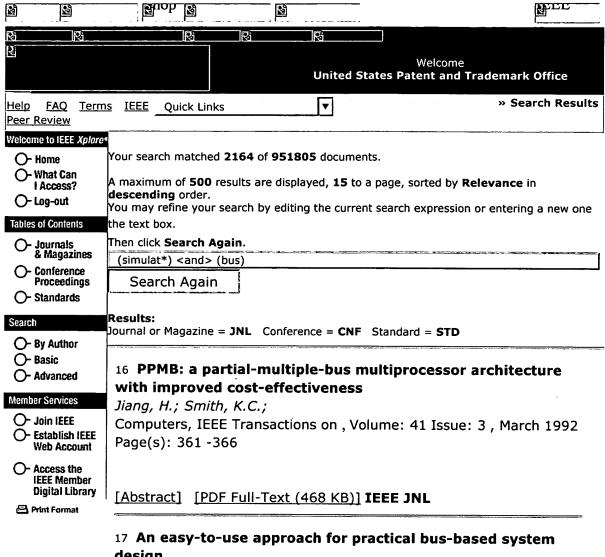
L Number	Hits	Search Text	DB	Time stamp
- Maumer	33204	((simulat\$3 or emulat\$3 or model\$4 or	USPAT;	2003/07/11 14:11
[33201	design\$3) same bus) and (IC or (integrated	US-PGPUB;	
		adj circuit) or semi?conductor or circuit or	EPO; JPO;	
		LSI or VLSI)	IBM TDB	
-	116	'''	USPĀT;	2003/07/10 17:15
		design\$3) same bus) and (IC or (integrated	US-PGPUB;	
		adj circuit) or semi?conductor or circuit or	EPO; JPO;	
		LSI or VLSI)) and Neuman\$ and harvard	IBM_TDB	0000/05/11 1/ 00
-	23	(((((simulat\$3 or emulat\$3 or model\$4 or	USPAT;	2003/07/11 14:09
		design\$3) same bus) and (IC or (integrated adj circuit) or semi?conductor or circuit or	US-PGPUB; EPO; JPO;	
1		LSI or VLSI)) and Neuman\$ and harvard) and	IBM TDB	
		collision) and (concurrent or simultaneous	12	
		or parallel or synchronous)		
-	20	(((((simulat\$3 or emulat\$3 or model\$4 or	USPAT;	2003/07/10 17:17
		design\$3) same bus) and (IC or (integrated	US-PGPUB;	
		adj circuit) or semi?conductor or circuit or	EPO; JPO;	
		LSI or VLSI)) and Neuman\$ and harvard) and	IBM_TDB	
		collision) and (concurrent or simultaneous		
		or parallel or synchronous)) and (paramater		
_	2	or variable or constant) (((((simulat\$3 or emulat\$3 or model\$4 or	USPAT;	2003/07/10 17:17
-	2	design\$3) same bus) and (IC or (integrated	US-PGPUB;	2003/07/10 17:17
		adj circuit) or semi?conductor or circuit or	EPO; JPO;	
		LSI or VLSI)) and Neuman\$ and harvard) and	IBM TDB	
		collision) and database	_	
-	2	,,,,,,,==============================	USPAT;	2003/07/10 17:18
		design\$3) same bus) and (IC or (integrated	US-PGPUB;	
		adj circuit) or semi?conductor or circuit or	EPO; JPO;	
		LSI or VLSI)) and Neuman\$ and harvard) and	IBM_TDB	
		collision) and (concurrent or simultaneous		
	-	or parallel or synchronous)) and (paramater or variable or constant)) and database		
_	23	1	USPAT;	2003/07/10 19:22
		design\$3) same bus) and (IC or (integrated	US-PGPUB;	
		adj circuit) or semi?conductor or circuit or	EPO; JPO;	
		LSI or VLSI)) and Neuman\$ and harvard) and	IBM_TDB	
		collision		
-	1476	'	USPAT;	2003/07/10 19:04
		design\$3) same bus) and ((IC or (integrated	US-PGPUB;	
		adj circuit) or semi?conductor or circuit) or LSI or VLSI) and buffer and collision	EPO; JPO; IBM TDB	
_	531		USPAT;	2003/07/10 19:21
	551	design\$3) same bus) same ((IC or (integrated	US-PGPUB;	
		adj circuit) or semi?conductor or circuit)	EPO; JPO;	
		or LSI or VLSI)) and buffer and collision	IBM_TDB	
-	1147	collision same bus same (transaction or	USPAT;	2003/07/10 19:22
		operation or instruction or function)	US-PGPUB;	
			EPO; JPO;	
		(13:	IBM_TDB	2002/07/20 20 55
_	112		USPAT;	2003/07/10 19:22
		operation or instruction or function)) same (simulat\$3 or emulat\$3 or model\$4 or	US-PGPUB; EPO; JPO;	
		design\$3)	IBM TDB	
-	51	((collision same bus same (transaction or	USPAT;	2003/07/10 19:29
		operation or instruction or function)) same	US-PGPUB;	
1		(simulat\$3 or emulat\$3 or model\$4 or	EPO; JPO;	
	}	design\$3)) and (bus same buffer) and	IBM_TDB	
		(concurrent or simultaneous or parallel or		
	_	synchronous)		0000/00/15 15 55
-	3	5907698.uref.	USPAT;	2003/07/10 19:32
			US-PGPUB; EPO; JPO;	
			IBM TDB	
-	1	5907698.pn.	USPAT;	2003/07/10 19:43
	_		US-PGPUB;	
			EPO; JPO;	
			IBM_TDB	
-	1	"5111413".PN.	USPAT	2003/07/10 19:32
-	1		USPAT	2003/07/10 19:32
	1		USPAT	2003/07/10 19:32

ſ <u>-</u>	1	"5541849".PN.	USPAT	2003/07/10 19:32
-		"5761079".PN.	USPAT	2003/07/10 19:32
_		collision with bus with (transaction or	USPAT;	2003/07/10 19:43
	300	operation or instruction or function)	US-PGPUB;	2003,07,10 15:13
		operation of imperaterion of function,	EPO; JPO;	
			IBM TDB	
_	248	(collision with bus with (transaction or	USPAT;	2003/07/10 19:44
	210	operation or instruction or function)) and	US-PGPUB;	2003, 07, 10 13:11
		(simulat\$3 or emulat\$3 or model\$4 or	EPO; JPO;	
		design\$3)	IBM TDB	
_	17		USPAT;	2003/07/10 19:45
		operation or instruction or function)) same	US-PGPUB;	2003, 01, 20 25125
		(simulat\$3 or emulat\$3 or model\$4 or	EPO; JPO;	
		design\$3)	IBM TDB	
_	1	5724504.pn.	USPAT;	2003/07/10 20:44
	-	3721301.pm.	US-PGPUB;	2003, 07, 10 20.44
			EPO; JPO;	
			IBM TDB	
_	1627	bus adj (design\$3)	USPAT;	2003/07/11 14:07
_	1027	bus auj (designos)	US-PGPUB;	2003/07/11 14:07
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
_	216	(bus adj (design\$3)) and collision	USPAT;	2003/07/11 14:07
_	210	(bus au) (design\$3); and collision	US-PGPUB;	2003/07/11 14:07
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
_	173	((bus adj (design\$3)) and collision) and	USPAT;	2003/07/11 14:08
-	1/3	(buffer or stack or FIFO)	US-PGPUB;	2003/07/11 14:08
		(buffer of stack of FIFO)	EPO; JPO;	
			DERWENT;	
			IBM TDB	
_	152	(((bus adj (design\$3)) and collision) and	USPAT;	2003/07/11 14:08
-	152	(buffer or stack or FIFO)) and (IC or	US-PGPUB;	2003/07/11 14:08
		(integrated adj circuit) or semi?conductor	EPO; JPO;	
		or circuit or LSI or VLSI)	IBM TDB	
	140	((((bus adj (design\$3)) and collision) and	USPAT;	2003/07/11 14:11
	140	(buffer or stack or FIFO)) and (IC or	1	2003/07/11 14:11
		(integrated adj circuit) or semi?conductor	US-PGPUB; EPO; JPO;	
		or circuit or LSI or VLSI)) and (concurrent	IBM TDB	
	1	or simultaneous or parallel or synchronous)	1 101 - 100	
_	104	(((((bus adj (design\$3)) and collision) and	USPAT;	2003/07/11 15:12
	104	(buffer or stack or FIFO)) and (IC or	US-PGPUB;	2003/07/11 13:12
		(integrated adj circuit) or semi?conductor	EPO; JPO;	
		1		
	1	or circuit or LSI or VLSI)) and (concurrent or simultaneous or parallel or synchronous))	IBM_TDB	
	1	and (simulat\$3 or emulat\$3 or model\$4)		
_	12101	bus same (simulat\$3 or emulat\$3 or model\$4)	USPAT;	2003/07/11 16:24
_	13191	Dub baile (billingach) of ellingach) of model94)	US-PGPUB;	2003/07/11 10:24
	1			
	[EPO; JPO;	
	3353	bug game (gimulates on amulates an mad-164)	IBM_TDB	2002/07/11 16:05
-	2358		USPAT;	2003/07/11 16:25
		same (collision or block\$2)	US-PGPUB;	
			EPO; JPO;	
	1		IBM_TDB	



design

Chung-Ho Chen; Feng-Fu Lin;

Computers, IEEE Transactions on , Volume: 48 Issue: 8 , Aug. 1999

Page(s): 780 -793

[Abstract] [PDF Full-Text (296 KB)] IEEE JNL

18 32-bit PI-bus versus 32-bit Futurebus+ performance comparison

Emmitt, J.;

Aerospace and Electronics Conference, 1993. NAECON 1993., Proceedings of the IEEE 1993 National, 24-28 May 1993 Page(s): 157 -164 vol.1

[Abstract] [PDF Full-Text (572 KB)] IEEE CNF

19 A high-speed, byte-serial, multiple-bus interc nnecti n netw rk

Armstrong, W.J.; Pohm, A.V.; Davis, J.A.; Communications, Computers and Signal Processing, 1989. Conference Proceeding., IEEE Pacific Rim Conference on , 1-2 June 1989

Page(s): 64 -69

[Abstract] [PDF Full-Text (440 KB)] IEEE CNF

20 Performance analysis of asynchronous hierarchical-bus multiprocessor systems using closed queuing network models

Mahmud, S.M.;

Circuits and Systems, 1990., IEEE International Symposium on , 1-3 May 1990

Page(s): 2689 -2692 vol.4

[Abstract] [PDF Full-Text (340 KB)] IEEE CNF

21 Optimal design of megabyte second-level caches for minimizing bus traffic in shared-memory shared-bus multiprocessors

Yen-Jen Oyang; Le-Chun Wu; System Sciences, 1992. Proceedings of the Twenty-Fifth Hawaii International Conference on , Volume: i , 7-10 Jan. 1992 Page(s): 467 -475 vol.1

[Abstract] [PDF Full-Text (460 KB)] IEEE CNF

22 Performance model for a prioritized multiple-bus multiprocessor system

Kurian, L.; Yu-Cheng Liu; Parallel and Distributed Processing, 1994. Proceedings. Sixth IEEE Symposium on , 26-29 Oct. 1994 Page(s): 577 -584

[Abstract] [PDF Full-Text (488 KB)] IEEE CNF

23 Modeling and evaluation of adaptive bus-preemption control with and without AVL systems

Gang-Len Chang; Vasudevan, M.; Chih-Chiang Su; Vehicle Navigation and Information Systems Conference, 1995. Proceedings. In conjunction with the Pacific Rim TransTech Conference. 6th International VNIS. 'A Ride into the Future', 30 July-2 Aug. 1995 Page(s): 305-316

[Abstract] [PDF Full-Text (832 KB)] IEEE CNF

24 Testing and evaluati n f batteries f r a fuel cell p wered hybrid bus

Miller, J.F.; Webster, C.E.; Tummillo, A.F.; DeLuca, W.H.; Energy Conversion Engineering Conference, 1997. IECEC-97. Proceedings of the 32nd Intersociety, 27 July-1 Aug. 1997 Page(s): 894 -898 vol.2

[Abstract] [PDF Full-Text (340 KB)] IEEE CNF

25 Network simulations of a general class of partial-connection multiple-bus systems

Tu, H.-Y.; Hawkes, L.W.; Modeling, Analysis and Simulation of Computer and Telecommunication Systems, 1999. Proceedings. 7th International Symposium on , 24-28 Oct. 1999 Page(s): 120 -127

[Abstract] [PDF Full-Text (124 KB)] IEEE CNF

26 Fast computations on a low-cost DSP-based shared-memory multiprocessor system

Christou, C.S.;

Electronics, Circuits and Systems, 2000. ICECS 2000. The 7th IEEE International Conference on , Volume: 1 , 17-20 Dec. 2000 Page(s): 189 -192 vol.1

[Abstract] [PDF Full-Text (352 KB)] IEEE CNF

27 Reducing power bus impedance at resonance with lossy components

Zeeff, T.M.; Hubing, T.H.; Electrical Performance of Electronic Packaging, 2001, 29-31 Oct. 2001 Page(s): 61-64

[Abstract] [PDF Full-Text (266 KB)] IEEE CNF

28 Computer modeling and simulation of the Optoelectronic Techn | gy C ns rtium (OETC) ptical bus

Whitlock, B.K.; Pepeljugoski, P.K.; Kuchta, D.M.; Crow, J.D.; Kang, S.-M.;

Selected Areas in Communications, IEEE Journal on , Volume: 15

Issue: 4, May 1997 Page(s): 717 -730

[Abstract] [PDF Full-Text (316 KB)] IEEE JNL

29 On the nature and inadequacies f transp rt timing delay c nstructs in VHDL descripti ns

Walker, P.A.; Ghosh, S.;

Computer-Aided Design of Integrated Circuits and Systems, IEEE

Transactions on , Volume: 16 Issue: 8 , Aug. 1997

Page(s): 894 -915

[Abstract] [PDF Full-Text (472 KB)] IEEE JNL

30 A bus-monitoring model for MPEG video decoder design

Nam Ling; Jui-Hua Li;

Consumer Electronics, IEEE Transactions on , Volume: 43 Issue: 3,

Aug. 1997

Page(s): 526 -530

[Abstract] [PDF Full-Text (556 KB)] IEEE JNL

[Prev] 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20 21 22 23 24 25 26 27 28 29 30 31 32 33 34 [Next]

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O- Advanced	1 A novel reduced swing CMOS bus interface circuit for high
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O- Join IEEE	Golshan, R.; Haroun, B.; Circuits and Systems, 1994. ISCAS '94., 1994 IEEE International
O- Establish IEEE	Symposium on , Volume: 4 , 30 May-2 June 1994
Web Account	Page(s): 351 -354 vol.4
O- Access the IEEE Member Digital Library	
Print Format	[Abstract] [PDF Full-Text (368 KB)] IEEE CNF
	2 Steady-state and transient ampacity of bus bar
	Coneybeer, R.T.; Black, W.Z.; Bush, R.A.;
	Power Delivery, IEEE Transactions on , Volume: 9 Issue: 4 , Oct.
	1994
	Page(s): 1822 -1829
	[Abstract] [PDF Full-Text (664 KB)] IEEE JNL
	<u> </u>

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